

# M Microscopes

## Model: XJP-6A, Metallurgical



Inverted Metallurgical Microscope is suitable to observe the object. It is achromatic objectives & wide-field eyepieces.

It provides clear & high-contrast picture, & with polarizer device, it is the ideal instrument in research work in metallography, mineralogy, precision engineering, electronics etc. it's suitable for scientific research, teaching demonstration, in the colleges & factory.

Note: in this table, "■" denotes a standard attachment, "○" denotes an optional accessory. Design change: To keep pace with technological advances, we have reserved the right to make design modifications & changes without notice.

Package dimension: 665mm x 310mm

Net weight: 14kg

Gross weight: 19kg

Order No.	Item	Standard Outfits	
		XJP-6	XJP-6A
	Main Body	■	■
SO9	Mechanical stage with a stroke of 75 by 50 & size of 180 by 155	■	■
EP10	Plan eyepiece 10X-18	■ ■	■ ■
EP12.5	Plan eyepiece 12X-14	■ ■	■ ■
EH5	Huygenian ocular 5X-20	○ ○	○ ○
EW10	Plan eyepiece 10X-20	○ ○	○ ○
Epr10b	Plan reticle eyepiece 10X-14	■	■
B-OAr4	Achromat objective 4/0.10	■	
M-OA10	Achromat objective 10/0.25	■	
M-OSPr40	S-plan achromat objective 40/0.65	■	
M-OAor100	Achromat objective 100/1.25oil	■	
B-OPr2.5	Plan achromat objective 2.5/0.07	○	○
B-OPr4	Plan achromat objective 4/0.10		○
M-OPr10	Plan achromat objective 10/0.25		■
M-OPr20	Plan achromat objective 20/0.35	○	■
M-OPr40a	Plan achromat objective 40/0.65		■
M-OSPor100	S-plan achromat objective 100/1.25 oil		■
9J-6	Stage plate(1)	■	■
9J-7	Stage plate(2)	■	■
9J-8	Stage plate(3)	■	■
9J-9	Stage plate(4)	○	○
9J-11	Stage plate holder	■	■
TBR03	Rotating binocular head(45oC)	■	■
LH01	Lamp housing	■	■
	Halogen lamp 6V30W	■ ■	■ ■
PO02	Polarizer	■	■
PA01	Analyzer	■	■
CL02	Specimen clamps	■	■
9J.7	Photo adaptor	○	○
EPHp5	Photo eyepiece S5X	○	○
EPHp6.3	Photo eyepiece S6.3X	○	○
EPHp0.65	Video eyepiece 0.65X	○	○
	Metallurgical microphotography equipments	○	○
	35mm DF camera with shutter release	○	○
SC03	Specimen holder	○	○
	Stage micrometer (division 0.01mm)	○	○

## Model: XJL-101A, Wafer inspection Microscopes



XJL-101 series the reflected light microscope is suitable to observe the microscopical surfaces of non-transparent object. It is equipped with large move range stage, vertical illumination, plan achromatic objectives and wide-field eyepieces. It provides clear and high-contrast picture, & with polarizer device, it is the ideal instrument in research work in metallography, mineralogy, precision engineering, electronics etc. it's suitable for scientific research, teaching demonstration, in the colleges & factory.

Model			XJL-101	XJL-101A	
Eyepieces	Wide Field	WF10X(Ø18mm)	■	■	
		WF16X(Ø11mm)	○	○	
	Plan Dividing	10X(0.10mm/div)	○	○	
Objectives	Plan achromatic (No cover glass)	Magnification/N.A	Work distance		
		PL5X/0.12	18.3	■	■
		PL10X/0.25	8.9	■	■
		PL25X/0.40	8.7	■	■
		PL40X/0.60	3.7	■	■
		PL50X/0.70	2.02	○	○
		PL80X/0.80	0.96	■	■
Eyepieces Tube	Trinocular	Compensation (inclination of 30°) Including analyzer		■	■
Stage	Size: 250x250mm can be move quickly. Move Range: 153x153mm		■		
	Size: 274x274mm can be move quickly. Move Range: 203x203mm			■	
Nosepiece	Backward inner locating on ball bearing	Quintuple	■	■	
CCD Camera Accessories	0.4xCCD Camera adapter		○	○	
	CCD Camera adapter		○	○	
	0.5xCCD Camera adapter with dividing		○	○	
	CCD Camera		○	○	
Illumination unit	Vertical illuminator 6V 20W halogen lamp. adjustable brightness, with polarizer		■	■	
Dig. Camera Adapter	CCD camera and accessories		○	○	